Using the values of magnetic moments measured by static method and effective magnetization data obtained from dynamic measurements we have estimated the real thicknesses of magnetic layers. It was found that decreasing of this thickness as compared to that assigned during sputtering occurs for the films with small content of silicon.

The model explaining the character of decreasing of magnetic layer saturation magnetization was proposed. It is based on formation of nonmagnetic silicides of metal. Within the framework of this model the magnetizations of structures with a various ratio of magnetic layer thickness to silicon layer one were calculated. The satisfactory coincidence with the results of experiment was shown.

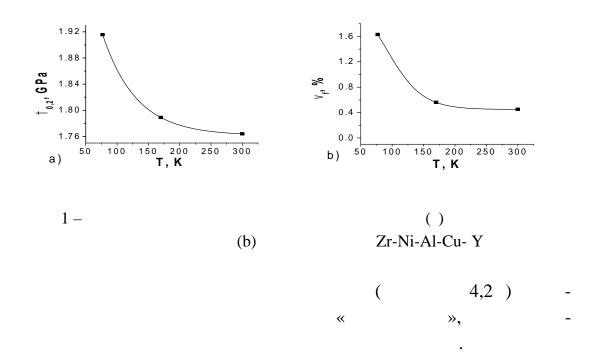
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       539.213.2
                    Zr-Al-Ni-Cu-Y
                                                               Zr-Al-Ni-Cu,
(Zr_{0.55}Al_{0.1}Ni_{0.05}Cu_{0.30})_{0.99}Y_{0.01}
```

```
– Zr (99,99 . %), Al (99,99 . %), Ni (99,99
                                                                              . %), Cu
           . %) Y (99,95 . %)
(99,99
                                                     Ar.
                                                      2
                      [1].
                                                                     -3
                                                           4,5
                                                                                  2
                                              3,35 10<sup>-4</sup> -1
                                                                                 =300 ,
170 , 77 4,2 .
                                             45°
                          LEO Stereoscan 440,
                                                                                 EDAX
                                  20
                                   0,2,
                                                         f•
 max
                                               . 1.
                                                        300 , 170
                                                                        77
                    4,2
                                                                                       1
                                            ( <sub>0,2</sub>, <sub>max</sub>
                                                        _{\rm f}
                      Zr-Ni-Al-Cu- Y
                                                       300 , 170 , 77
                                                                          4,2
                                                             <sub>f</sub>, %
                       Τ,
                                  0,2,
                                               max,
                        300
                                   1,742
                                               1,769
                                                            0,45
                        170
                                   1,787
                                               1,789
                                                            0,56
                        77
                                   1,916
                                                            2,45
                                               1,987
                        4.2
                                               1,801
                                                            0,00
```

300 - 77  $_{0,2}$   $_{f}$  ( 1 , b). ,

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: 535.312.539

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